

L Number	Hits	Search Text	DB	Time stamp
1	494	33/645.ccls.	USPAT	2003/07/02 07:09
2	2131	430/22,311.ccls.	USPAT	2003/07/02 07:09
3	489	356/399.ccls.	USPAT	2003/07/02 07:09
4	0	250/491.2.ccls.	USPAT	2003/07/02 07:09
5	1136	438/706,717,725.ccls.	USPAT	2003/07/02 07:10
6	4195	33/645.ccls. 430/22,311.ccls. 356/399.ccls. 250/491.2.ccls. 438/706,717,725.ccls.	USPAT	2003/07/02 07:10
7	405	(33/645.ccls. 430/22,311.ccls. 356/399.ccls. 250/491.2.ccls. 438/706,717,725.ccls.) and alignment near mark\$1	USPAT	2003/07/02 07:11
-	6399	alignment near mark\$1 and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/07/02 07:09
-	1787	(alignment near mark\$1 and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:02
-	559	expose\$3 near7 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	1427	expos\$3 near7 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	1210	expos\$3 near5 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
-	471	(expos\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:07
-	146	clear\$3 near5 (alignment near mark\$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
-	69	(clear\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
-	77	(clear\$3 near5 (alignment near mark\$1) and semiconductor) not ((clear\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
-	0	chung near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
-	0	chuang near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	1	chuang near chieh and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	249	lin and alignment near mark\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	121	(lin and alignment near mark\$1) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
-	3	("6057206"   "6197481"   "6207966").PN.	USPAT	2003/06/17 08:44

-	16	("4981529"   "5382545"   "5407763"   "5596230"   "5686761"   "5705080"   "5733711"   "5858588"   "5882980"   "5904563"   "5923996"   "5926720"   "5943587"   "6060787"   "6100158"   "6143622").PN.	USPAT	2003/06/17 08:47
-	13	("3783044"   "5128283"   "5316966"   "5356513"   "5578519"   "5627110"   "5877562"   "5889335"   "5893744"   "5911108"   "5946583"   "5950093"   "5982044").PN.	USPAT	2003/06/17 08:58
-	435	((expos\$3 near5 (alignment near mark\$1) and semiconductor) and photoresist) not (clear\$3 near5 (alignment near mark\$1) and semiconductor)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:08
-	13	((("6197481") or ("6184104") or ("6529274") or ("6049137") or ("4632724") or ("6057206") or ("5897371") or ("5899738") or ("5946583") or ("5627110") or ("5316966") or ("5902707") or ("5705320")).PN.	USPAT	2003/06/23 13:26